

Contact and Fees

X-ray Diffraction Facility and Solid State Characterization Core Lab

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USF ACADEMIC USERS		
Service	FEE [\$/HR]	Typical charge for one sample (may vary depending on sample / range)
Single Crystal Diffractometer (SCXRD) Please see the second page for co-authorship policy	20	\$60-\$240
Powder Diffractometer (PXRD)	20	\$5.33 (16min) (3-50 2theta, 0.01deg step, 0.2sec/step)
TGA	20	\$20 (25 – 600 °C, 10°C / minute)
DSC	20	\$20 (25 – 400 °C, 10 °C / minute)
IR	150	\$5 (Base line + scan 4000 – 400 cm-1, 8 scan accumulation)

NON USF ACADEMIC USERS		
Inquire (Iwojtas@usf.edu)		

COMMERCIAL USERS / USF NON ACADEMIC USERS Inquire (Iwojtas@usf.edu)

Co-authorship and Acknowledgment Policy

The following guidelines should be used to determine if X-ray crystallographer should be included as a co-author for a publication or if an acknowledgement is sufficient. These guidelines are in accord with recommendations from the American Crystallographic Association and consistent with co-authorship guidelines set forth by most academic journals.

Co-authorship:

Crystallographer should be included as a co-author if:

- structural information derived from the X-ray diffraction experiment is a critical part of the intellectual content of the paper and the structural information has been derived mainly from the diffraction data;
- structural data and models being published require significant input from crystallographer and use of crystallographer's expertise in data processing, modeling and analysis of results;

Acknowledgement:

Acknowledgement only is sufficient in case the structural information was derived from routine data collection and analysis, performed by crystallographer, user or lab assistant, is not a critical part of the intellectual content of the paper and constitutes only minor part of the publication.